



5/9/2009

RELIABILITY MONITOR REPORT
FOR

MFN Standard Metal Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

7705201XC	DG211CSE+	MAX1232CPA+	MAX232CSE	MAX232MLP
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The calculated failure rate for devices using this process is:

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and

Process Information:

Process Description: MFN Standard Metal Gate CMOS

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0802	DG211CSE+	150C	1000 HRS	80	0	NRCAEA194B
STORAGE LIFE	0804	MAX1232CPA+	150C	1000 HRS	80	0	NPPADA675B
STORAGE LIFE	0805	MAX232CSE	150C	1000 HRS	80	0	NHUBBA6Q9B
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0804	MAX1232CPA+	-65C TO 150C	1000 CYS	80	0	NPPADA675B
TEMP CYCLE, 5' RAMP, 10' DWELL	0817	MAX232MLP	-65C TO 150C	1000 CYS	78	0	NPWBDA081Q1
TEMP CYCLE, 5' RAMP, 10' DWELL	0817	MAX232MLP	-65C TO 150C	500 CYS	78	0	NPWBDA081Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	0818	MAX232MLP	-65C TO 150C	1000 CYS	78	0	NPWBDA081Q3
TEMP CYCLE, 5' RAMP, 10' DWELL	0833	7705201XC	-65C TO 150C	1000 CYS	80	0	NROBCK108Q1
TEMP CYCLE, 5' RAMP, 10' DWELL	0833	7705201XC	-65C TO 150C	500 CYS	80	0	NROBCK108Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	0833	7705201XC	-65C TO 150C	500 CYS	80	0	NROBCK108Q3
TEMP CYCLE, 5' RAMP, 10' DWELL	0833	7705201XC	-65C TO 150C	1000 CYS	80	0	NROBCK108Q3
Total:						0	